PA200/AP200-BlueRay

. C

 \bigcirc

Fastest production testing without compromising accuracy

Operation lamp for machine status

Instrument shelf for easy access to measurement equipment

Universal platen setup -

• For use with DC and RF positioners and probe cards

Base machine

- 200 mm x/y stage for reliable 24/7 operations
- Low maintenance
- Designed for fast die stepping up to 10 die/sec
- High-accurate Z-stage for minimum scrub mark

Chuck

- Conductive chuck surface with vacuum holes for thin wafers
- Integrated AUX sites for calibration and cleaning sites
- Thermal test capability (25° C to 150° C)

Integrated vibration isolation system -

- Eliminates vibration from external sources (acoustic, architectural, etc.)
- Enhances system stability
- Reduces damage to pads, wafers and probe tips

Powerful ProberBench[™] operating environment

- Stable, Linux-based controller
- Realtime PID motion controller
- Z-Profiling: Automatic wafer warpage compensation
- Integrated, reliable industrial PC for running ProberBench software

Small footprint machine table

- Integrates all prober components and supplies
- Integrated rollers

© Copyright 2011 Cascade Microtech, Inc. All rights reserved. Cascade Microtech is a registered trademark, and ProberBench is a trademark of Cascade Microtech, Inc. All other trademarks are the property of their respective owners.

Data subject to change without notice

PA/AP200BR-PH-0911

Engineering prober screen

- Operate machine in a semi-automatic engineering mode
- Free die-to-die navigation on wafer
- Individual die testing

Advanced software automation tools

- PACE Easy to use control environment for production testing
- Powerful pattern recognition software
- Including a flexible interface for tester integration

Microscope

• High-resolution optics for probe inspection, wafer navigation and alignment

Expert control panel

- Comfortable use without PC
- Full control of all probe stages with position feedback
- Entire system control from one panel
- Analog joystick for precise, sub-micron positioning
- Point-and-shoot navigation

Loader module

- Universal cassette stand for substrates from 2" to 8"
- Integrated pre-aligner for flat/notch detection
- Barcode/2D Matrix code/0CR wafer code recognition
- Field upgradeable

PA200 DS BlueRay

Cartan and a state of the

Chuck for double-sided substrates

Measurement instrumentationPrepared for 4" integrating sphere, fiber optics





PACE Prober Automation Control Environment

Prober user interface for fully-automatic production systems



Vision screen

- Embedded SPECTRUM™ Vision System
- Point-and-Shoot navigation
- Alignment training wizards

Wafermap progress

• Visualization of current probelocation and test bin

Substrate ID information

- 40 mm travel range for maximum flexibility
- System height can adapt easily from wafer to package board application

Cassette mapping

- Visualization of slots (used, cross-slotted, tested)
- Wafer-ID / slot

Pass / Fail statistics



Full screen GUI

• Full screen, multi page design Conform to SEMI E95

• Easy navigation between screens using function keys

• Buttons enabled depending on user rights

Equipment status — • Current machine task

• Operation lamp status

©Copyright 2011. Cascade Microtech, Inc. All rights reserved. Cascade Microtech and SPECTRUM are trademarks of Cascade Microtech, Inc. All other trademarks are the property of their respective owners.

Data subject to change without notice

PACE-PH-0911

Gratan- Idu	W2N2011 3-11-18 PM	¢	RECIPE	ACTION COUNT
	Mathine is	ready to start		Instate Locked
	Procest	Separat		
Towalates			Spence	Land Project
Louiser			Perty tystem leady	
Scan Coperfi readly by Call Select Market In add Coperfi colored works In add Walfer	ter in texach in Deleo ter Heleo in		Lis Denkog Wully holds Cold Clocks spelvers Align Wolf y AC Karl Lisad Denveller Holing Well Scott Fr	Sive Project
Miller.			X Seal Rater	See Desire
UK BIROS Radio Office Decisioner Folle Dece	d d		Volly Velor ID Volly Velor Start Alap/Velor ar trading	
Sognification Record Alars	a a		C Wire Bracks	
Daf + Diales				Deser
Thereof.	haub.			
HI GLAP IN	ongo alian			Part of the second seco
Canveran				United: Rep-Bid
Raber Carri Recording to	onerd genera			
OUNTER				
Halfs Lat 2 reads frozie medi techni Radi Soffe Frank Roher Radi II Soffe Radi II Soffe	at God Stat stoy scher schensen 12			
Spectrum				
hamolisie lagroste latolign basciskele	Ovietim			
P.C.	v Poter		ander 17 19 19	

Recipe editor

- Simple creation of test sequence
- Build sequences by Drag'n'drop from function library to sequence list
- Easy customization



Engineering prober screen

- Operate machine in a semiautomatic engineering mode
- Free die-to-die navigation on wafer
- Individual die testing



PACE Prober Automation Control Environment

Prober user interface for fully-automatic production systems



Vision Screen

- Embedded SPECTRUM™ Vision System
- Point-and-Shoot navigation
- Alignment training wizards

Wafermap progress

• Visualization of current probelocation and test bin

Substrate ID information -

- 40 mm travel range for maximum flexibilitySystem height can adapt easily from wafer to pack-
- age board application

Cassette Mapping -

- Visualization of slots (used, cross-slotted, tested)
- Wafer-ID / slot

Pass / Fail statistics -



Full screen GUI

Full screen, multi page designConform to SEMI E95

Equipment Status — • Current machine task

• Operation lamp status

©Copyright 2011. Cascade Microtech, Inc. All rights reserved. Cascade Microtech and SPECTRUM are trademarks of Cascade Microtech, Inc. All other trademarks are the property of their respective owners.

Data subject to change without notice

PACE-PH-0911

Status: Ide	8/29/2011 2:14:48 PM	Gascar					RECIP	E				Access: Admin	Login	
	Machine is	s ready	to start									x	systick Locked	
Water Descrip	Son Process	Sequence												
Templates				Sequence			_	_	_	_	_	_	_	Load Project
Loader				 Verify ty Lot Dials 	stem kenay									
Scan Cassette				Verify Pr	u abe Card								_	Save Project
Select Water D	ielon			Check Sp	here Alian									
Load Cassette	Dialog			Verify Lo	t Start									
Unload Wafer				Load Cas	sette Dialog									Load Recipe
1001 1101				Scan Cas	sette									
Wafer				S Load Wal	ler								_	Same Recipe
Lot Dialog				Verify Wa	sfer 10									
ProbeOffsetDia	log			Verity Wa	der Start								_	
Wafer Stepping				B Z-Dreffler										Claur
SetProbeOffsel				B Wafer St	rosino								_	
ScopePosition Marcal Manual														100
Z-Profiling														
CleanProbe														0
waterbady														00wil
Thermothu	ck													Remove
Common	perature .													Unlock Joystick
Danker Common														
Pause	~													
Show Message	Bax													
BlueRay														
Verfy Lut Start Verfy Probe Cr Verfy SOTRea Check Sphere A End Of Lot Can Verfy Wafer II Sectors	nd sert by Ngn firmation													
spectrum														
Alig/Hater	ceccon													
AutoAlign														
ReadDataNatri	×													
F2 Overview	F3 Prober	Ľ	F4 tsion	F5 Handler		F7 Setup	F8 History							F1 Help

Recipe Editor

- Simple creation of test sequence
- Build sequences by Drag'n'drop from function library to sequence list
- Easy customization



Engineering Prober Screen

- Operate machine in a semiautomatic engineering mode
- Free die-to-die navigation on wafer
- Individual die testing

